

---

**Mehanska standardizacija polprevodniških elementov - 1. del: Splošna pravila za pripravo tehničnih risb diskretnih elementov (IEC 60191-1:2007)**

Mechanical standardization of semiconductor devices -- Part 1: General rules for the preparation of outline drawings of discrete devices

Mechanische Normung von Halbleiterbauelementen -- Teil 1: Allgemeine Regeln für die Erstellung von Gehäusezeichnungen von Einzelhalbleiterbauelementen

Normalisation mécanique des dispositifs à semi-conducteurs. - Partie 1: Règles générales pour la préparation du dessin des boîtiers des dispositifs à semi-conducteurs

[https://standards.iteh.ai/catalog/standards/sist/3493e493-3215-4c29-aca2-](https://standards.iteh.ai/catalog/standards/sist/3493e493-3215-4c29-aca2-d31b47986a53/sist-en-60191-1-2008)

[d31b47986a53/sist-en-60191-1-2008](https://standards.iteh.ai/catalog/standards/sist/3493e493-3215-4c29-aca2-d31b47986a53/sist-en-60191-1-2008)

**Ta slovenski standard je istoveten z: EN 60191-1:2007**

---

**ICS:**

01.100.25	Risbe s področja elektrotehnike in elektronike	Electrical and electronics engineering drawings
31.080.01	Polprevodniški elementi (naprave) na splošno	Semiconductor devices in general
31.240	Mehanske konstrukcije za elektronsko opremo	Mechanical structures for electronic equipment

**SIST EN 60191-1:2008**

**en,de**

**iTeh STANDARD PREVIEW**  
**(standards.iteh.ai)**

SIST EN 60191-1:2008

<https://standards.iteh.ai/catalog/standards/sist/3493e493-3215-4c29-aca2-d31b47986a53/sist-en-60191-1-2008>

EUROPEAN STANDARD  
NORME EUROPÉENNE  
EUROPÄISCHE NORM

**EN 60191-1**

June 2007

ICS 31.080.01

English version

**Mechanical standardization of semiconductor devices -  
Part 1: General rules for the preparation  
of outline drawings of discrete devices  
(IEC 60191-1:2007)**

Normalisation mécanique des dispositifs  
à semi-conducteurs -  
Partie 1: Règles générales  
pour la préparation du dessin  
des boîtiers des dispositifs  
à semi-conducteurs  
(CEI 60191-1:2007)

Mechanische Normung  
von Halbleiterbauelementen -  
Teil 1: Allgemeine Regeln  
für die Erstellung  
von Gehäusezeichnungen  
von Einzelhalbleiterbauelementen  
(IEC 60191-1:2007)

**ITeh STANDARD PREVIEW  
(standards.iteh.ai)**

This European Standard was approved by CENELEC on 2007-05-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Cyprus, the Czech Republic, Denmark, Estonia, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland and the United Kingdom.

**CENELEC**

European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**Central Secretariat: rue de Stassart 35, B - 1050 Brussels**

## Foreword

The text of document 47D/678/FDIS, future edition 2 of IEC 60191-1, prepared by SC 47D, Mechanical standardization for semiconductor devices, of IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60191-1 on 2007-05-01.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2008-02-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2010-05-01

Annex ZA has been added by CENELEC.

---

## Endorsement notice

The text of the International Standard IEC 60191-1:2007 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated:

IEC 60191-6

NOTE Harmonized as EN 60191-6:2004 (not modified).

**iTeh STANDARD PREVIEW**  
**(standards.iteh.ai)**

---

SIST EN 60191-1:2008

<https://standards.iteh.ai/catalog/standards/sist/3493e493-3215-4c29-aca2-d31b47986a53/sist-en-60191-1-2008>

## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60191-2 + supplements + amendments	1966	Mechanical standardization of semiconductor devices - Part 2: Dimensions	-	-
IEC 60191-4	- <sup>1)</sup>	Mechanical standardization of semiconductor devices - Part 4: Coding system and classification into forms of package outlines for semiconductor device packages	EN 60191-4	1999 <sup>2)</sup>
ISO 370 <sup>3)</sup>	- <sup>1)</sup>	Toleranced dimensions - Conversion from inches into millimetres and vice versa	-	-

iTech STANDARD PREVIEW  
(standards.iteh.ai)

SIST EN 60191-1:2008

<https://standards.iteh.ai/catalog/standards/sist/3493e493-3215-4c29-aca2-d31b47986a53/sist-en-60191-1-2008>

<sup>1)</sup> Undated reference.

<sup>2)</sup> Valid edition at date of issue.

<sup>3)</sup> ISO 370 has been withdrawn on 2000-05-18.

**iTeh STANDARD PREVIEW**  
**(standards.iteh.ai)**

SIST EN 60191-1:2008

<https://standards.iteh.ai/catalog/standards/sist/3493e493-3215-4c29-aca2-d31b47986a53/sist-en-60191-1-2008>

# INTERNATIONAL STANDARD

**IEC**  
**60191-1**

Second edition  
2007-04

---

---

## Mechanical standardization of semiconductor devices –

### Part 1: General rules for the preparation of outline drawings of discrete devices

(standards.iteh.ai)

SIST EN 60191-1:2008

<https://standards.iteh.ai/catalog/standards/sist/3493e493-3215-4c29-aca2-d31b47986a53/sist-en-60191-1-2008>



Commission Electrotechnique Internationale  
International Electrotechnical Commission  
Международная Электротехническая Комиссия

PRICE CODE

**W**

*For price, see current catalogue*

## CONTENTS

FOREWORD.....	4
1 Scope and object.....	6
2 Normative references .....	6
3 Terms and definitions .....	6
4 General rules for all drawings .....	8
4.1 Drawing layout .....	8
4.2 Dimensions and tolerances .....	8
4.3 Methods for locating the datum .....	10
4.4 Numbering of terminals .....	10
5 Additional rules .....	12
5.1 Rules for device and case outline drawings .....	12
5.2 Rules to specify the dimensions and positions of terminals.....	12
5.3 Rules for gauge drawings.....	13
6 Inter-conversion of inch and millimetre dimensions and rules for rounding off.....	13
7 Rules for coding .....	14
Annex A (informative) Reference letter symbols.....	15
Annex B (normative) Standardization philosophy.....	18
Annex C (informative) Rules to specify the dimensions and positions of terminals on a base drawing .....	23
Annex D (normative) General philosophy of flat base devices.....	30
Annex E (informative) Examples of semiconductor device drawing .....	32
Annex F (informative) Former rules for rounding off .....	36
Annex G (informative) Former rules for coding.....	38
Bibliography.....	39
Figure 1 – Numbering of terminals of lozenge – shaped bases.....	11
Figure 2 – System to indicate the dimensions of the terminals .....	13
Figure B.1 – Example of rigid lug device .....	21
Figure B.2 – Example of flexible terminal device .....	22
Figure C.1 – Circular base outline with no tab.....	27
Figure C.2 – Tolerances of terminals .....	27
Figure C.3 – Gauge for a circular base outline with no tab .....	28
Figure C.4 – Circular base outline with tab.....	29
Figure C.5 – Gauge for a circular base outline with tab.....	29
Figure D.1 – Example of flat base outline.....	31
Figure E.1 – Long form package .....	32
Figure E.2 – 3 types of post/stud mount packages .....	32
Figure E.3 – 2 types of cylindric packages .....	33
Figure E.4 – Oval package, terminals in line .....	34



Figure E.5 – Cylindric package with different terminations .....	34
Figure E.6 – Flange mount package.....	34
Figure E.7 – Disk button package with 3 terminations .....	35
Figure E.8 – Special shape for bolt-fixture .....	35
Table A.1 – Dimensions of reference letter symbols.....	15

**iTeh STANDARD PREVIEW**  
**(standards.iteh.ai)**

SIST EN 60191-1:2008

<https://standards.iteh.ai/catalog/standards/sist/3493e493-3215-4c29-aca2-d31b47986a53/sist-en-60191-1-2008>

## INTERNATIONAL ELECTROTECHNICAL COMMISSION

**MECHANICAL STANDARDIZATION OF SEMICONDUCTOR DEVICES –****Part 1: General rules for the preparation of outline drawings  
of discrete devices**

## FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC provides no marking procedure to indicate its approval and cannot be rendered responsible for any equipment declared to be in conformity with an IEC Publication.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 60191-1 has been prepared by subcommittee 47D: Mechanical standardization for semiconductor devices, of IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition published in 1966 together with supplements 60191-1A:1969, 60191-1B:1970 and 60191-1C:1974 and constitutes a technical revision. The main changes from the previous edition are as follows:

- requirement added for SI-dimensions for new drawings to be published;
- former rules concerning inch-dimensions are given in an informative annex;
- former rules for coding are given in an informative annex;
- incorporation of the supplements;
- updating of references;
- restructuring and renumbering.

The text of this standard is based on the following documents:

FDIS	Report on voting
47D/678/FDIS	47D/682/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The IEC 60191 series, published under the general title *Mechanical standardization of semiconductor devices*, comprises the following parts:

- Part 1: General rules for the preparation of outline drawings of discrete devices
- Part 2: Dimensions
- Part 3: General rules for the preparation of outline drawings of integrated circuits
- Part 4: Coding system and classification into forms of package outlines for semiconductor device packages
- Part 5: Recommendations applying to integrated circuit packages using tape automated bonding (TAB)
- Part 6: General rules for the preparation of outline drawings of surface mounted semiconductor device packages

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

[SIST EN 60191-1:2008](https://standards.iteh.ai/catalog/standards/sist/3493e493-3215-4c29-aca2-d31b47986a53/sist-en-60191-1-2008)

- reconfirmed; <https://standards.iteh.ai/catalog/standards/sist/3493e493-3215-4c29-aca2-d31b47986a53/sist-en-60191-1-2008>
- withdrawn;
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

# MECHANICAL STANDARDIZATION OF SEMICONDUCTOR DEVICES –

## Part 1: General rules for the preparation of outline drawings of discrete devices

### 1 Scope and object

This part of IEC 60191 gives guidelines on the preparation of outline drawings of discrete devices.

NOTE For preparation of outline drawings of surface mounted discrete devices, IEC 60191-6 should be referred to as well.

The primary object of these drawings is to indicate the space which should be allowed for devices in an equipment, together with other dimensional characteristics required to ensure mechanical interchangeability.

It should be noted that complete interchangeability involves other considerations such as the electrical and thermal characteristics of the semiconductor devices concerned.

The international standardization represented by these drawings therefore encourages the manufacturers of devices to comply with the tolerances shown on the drawings in order to extend their range of customers internationally. It also gives equipment designers an assurance of mechanical interchangeability between the devices obtained from suppliers in different countries, provided they allow the space in their equipment that is indicated by the drawings and take note of the more precise information on bases, studs, etc.

NOTE Additional details on the standardization philosophy used in this standard are given in Annex B.

### 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60191-2:1966, *Mechanical standardization of semiconductor devices – Part 2: Dimensions* (including all supplements and amendments)

IEC 60191-4, *Mechanical standardization of semiconductor devices – Part 4: Coding system and classification into forms of package outlines for semiconductor device packages*

ISO 370, *Toleranced dimensions – Conversion from inches to millimetres and vice versa (withdrawn 2000-05)*

### 3 Terms and definitions

For the purposes of this document, the following definitions apply.

#### 3.1

##### **device outline drawing**

drawing which includes all dimensional characteristics required for the mechanical interchangeability of the complete device. It includes the case or body, all terminals and the locating tab if present

**3.2****terminal**

that part of the semiconductor device primarily used in making an electrical, mechanical or thermal connection. Examples of terminals are flexible leads, rigid leads, pins, studs, etc.

**3.3****case outline drawing**

drawing which includes all dimensional characteristics required for the mechanical interchangeability of the case or body. It does not include the dimensions of the terminals or the locating tab if present, but their positions are shown by dotted lines

**3.4****base drawing**

drawing which includes all dimensional characteristics required for the mechanical interchangeability of the terminals and mechanical index

NOTE 1 Examples of these characteristics are: lead length, lead diameters with controlled zones, lead spacing, pitch circle diameter, thickness, width and length of a tab, etc

NOTE 2 The diameter or major axis of the case outline should not be given on the base drawing.

NOTE 3 Many semiconductor devices have identical cases, but differ in the number or the length of terminals. It is also possible to have the same type of base associated with cases which are not identical.

Consequently, there are advantages in having:

a) a single drawing including only the dimensional characteristics of the case outline and separate drawings for the various bases which can be associated with this case outline,

or

b) a single drawing including only the dimensional characteristics of the base and separate drawings for the various case outlines which can be associated with this base.

**3.5****mechanical index**

locating feature, or that portion of the device specifically designed to provide orientation.

NOTE Examples of a mechanical index are: key, keyway, locating tab, etc.

**3.6****visual index**

any single terminal (or omission of) readily distinguished by the eye from others or any distinctive boss, stippled pattern or colour mark adjacent to a terminal

**3.7****datum**

a theoretically exact geometric reference (such as axes, planes, straight lines etc.) to which toleranced features are related. Datums may be based on one or more datum features of a part

[ISO 5459:1981, definition 3.1]

**3.8****seating plane or seating base**

reference plane from which, in general, outline and base dimensions are given

**3.9****seated height or mounted height**

distance from the seating plane to the top of any exposed tip or rigid terminal present, otherwise to the top of the outline. Flexible terminals should not be included as part of the seated height, but the mounted height should include a minimum allowance necessary for an axially mounted flexible lead to be bent at right angles